

Notice of References Cited

Application/Control No.

10/537,329

Applicant(s)/Patent Under

Reexamination

NAKAYAMA ET AL.

Examiner

LOIS ZHENG

Art Unit

1793

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,259,937	11-1993	Hatano et al.	205/149
B	US-			
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E	US-			
F	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

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N	JP04-107290	04-1992	Japan	Nishimura et al.	C25D 11/34
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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